

ETS 2020 BEST PAPER

The European Test Symposium (ETS) Best Paper Award, which was introduced in 2004 when the European Test Workshop (ETW) turned into the ETS, aims to maintain and encourage the high quality of papers and presentations in the ETS technical program.

Eligible for the ETS Best Paper Award are papers published in the Formal Proceedings of ETS and presented in a full-length oral presentation slot in the regular technical program. The Best Paper is selected by the Best Paper Selection Committee (BPSC), appointed by the Program Committee, taking into account the inputs from reviewers, Topic Chairs and symposium attendees, as follows:

- *Reviewers*
A list of candidate papers was created in the review process.
- *Topic Chairs and BPSC Members*
For all candidate papers, Topic Chairs and several BPSC members attended the oral presentation to judge both the technical quality of the work and the quality of the presentation.
- *Audience*
The candidate papers were labeled as such in the program, and the attendees had the chance to vote for the best paper.

Based on these inputs, the BPSC recommended the paper to be awarded and the final decision was taken by the Program Committee.

It is our pleasure to announce that the Best Paper Award of ETS'20 goes to the paper entitled:

“Latent Defect Screening with Visually-Enhanced Dynamic Part Average Testing”

by

Anthony COYETTE¹, Wim DOBBELAERE¹, Ronny VANHOOREN¹,
Nektar XAMA², Jhon GOMEZ², Georges GIELEN²

¹ON Semiconductor, Belgium

²KU Leuven, Belgium

The award is formally handed over during the plenary opening session of ETS'21.

Sybille Hellebrand
Paderborn University, DE
ETS'20 Award Co-Chair

Jerzy Tyszer
Poznan University of Technology, PL
ETS'20 Award Co-Chair